

<b>Notice of References Cited</b>	Application/Control No. 10/045,112	Applicant(s)/Patent Under Reexamination BENANTAR, MESSAOUD	
	Examiner Shin-Hon Chen	Art Unit 2131	Page 1 of 1

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*	B	US-2002/0087859	07-2002	Weeks et al.	713/156
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	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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